

**Notice of References Cited**

Application/Control No.

10/662,490

Applicant(s)/Patent Under  
Reexamination  
BAAN, JACOB DE

Examiner

Ajay Vasudeva

Art Unit

3617

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,182,660	02-2007	De Baan, Jacob	441/5
*	B	US-7,114,883	10-2006	De Baan, Jacob	405/206
*	C	US-7,107,925	09-2006	Wille et al.	114/230.15
*	D	US-6,915,753	07-2005	De Baan, Jacob	114/230.14
*	E	US-6,546,739	04-2003	Frimm et al.	62/50.2
*	F	US-6,485,343	11-2002	B.o slashed.rseth, Knut	441/4
*	G	US-3,741,264	06-1973	Kinoshita, Yoshiaki	141/383
*	H	US-3,479,673	11-1969	MANNING WILLIAM F	114/264
*	I	US-3,380,091	04-1968	FRANCIS SAURIN BRENDAN; et. al.	441/3
*	J	US-3,354,479	11-1967	DICKSON ALEXANDER F; et. al.	441/5
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
X	N	GB 2328196 A	02-1999	United Kingdom	DE, BAAN JACOB	
	O	FR 2579558 A	10-1986	France	BERTHET et al.	
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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